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X-ray diffraction study of NaF nano-crystals in photo-thermorefractive glass

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Abstract:

PTR glass is a photosensitive silicate glass which imparts refractive index change after UVexposure and thermal development. The origin of photosensitivity is explained by the precipitation of NaF crystals inside the glass matrix. While nucleation of NaF in PTR glass has been thoroughly studied, the mechanisms of growth of NaF crystals have drawn a limited interest. To study the NaF growth, several techniques were combined: optical spectroscopy, interferometry, DSC and XRD. It was found that the size of NaF crystals in UV-exposed PTR glass, as determined by the broadening of the diffraction lines does not exceed ~20 nm. The NaF crystals growth is limited by the exhaustion of Na⁺F⁻ within the glass matrix as well as the increase of the glass transition temperature of the glass surrounding the crystals that act as a barrier for further growth. X-ray diffraction analysis of NaF powder allowed calculating the crystals' volume fraction and their average size. Combination of these parameters with Rayleigh scattering model allowed predicting scattering at any wavelength and any thermal treatment, proving that scattering is determined by single crystals.

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1. Introduction

Photo-thermo-refractive (PTR) glass is a photosensitive Na-Al-Zn-K-F-Br-silicate glass, doped with Ce, Ag, Sb, and Sn, that undergoes a permanent refractive index change after UV-exposure followed by thermal treatment [1-2]. PTR glass has been used for the fabrication of various types of volume diffractive optical elements [3], it finds a wide range of applications such as spectral beam combining, selection of transverse and longitudinal modes in laser resonators, beam deflectors, splitters and attenuators [4]. A tentative description of the photo-induced reactions can be summarized as [5]: (i) oxidation of Ce^{3+} and formation of metallic silver during exposure to UV-radiation $(Ag^+ + Ce^{3+} \rightarrow Ag^0 + Ce^{4+})$, (ii) silver clustering during a first high temperature thermal treatment, and (iii) heterogeneous nucleation and growth of NaF nano-crystals on further heating. Other intermediate phases, such as AgBr or NaBr, for instance, might also form and thus the detailed nucleation mechanism of PTR glass is not yet clear. Moreover, these substances are very hard to detect using conventional characterization techniques and might contribute to losses in PTR glass. In any case, after thermal treatment, PTR glass crystallizes partially, and a small fraction of nanometric NaF crystals appears embedded in the glass matrix [6,7]. This photothermo-induced crystallization contributes to scattering losses.

Knowledge about the crystallization mechanisms involved in the photo-induced reactions in PTR glass throughout the various steps of thermal development is incomplete; a characterization of the complex crystallization process in such partially crystallized glass could shed some light into this matter. It should be noted that a thorough micro-structural analysis of PTR glass is complicated due to the nano-metric scale (crystals typically are 20 nm in diameter) and small volume fraction (typically between 0.1 and 2 vol.%) of the phases formed after the standard low

temperature thermal treatment processing used for the development of holographic optical elements. An important peculiarity of PTR glass is that nucleation and crystallization of NaF are controlled by the very low content of some key elements involved in the crystallization process, such as Ag, F and Br [8]. This fact must significantly impact the kinetics of phase formation, and hence is of great interest for a detailed study.

The aim of this study was to quantify the evolution of NaF crystals parameters and correlate them with the optical characteristics of PTR glasses. In order to accomplish this, X-Ray Diffraction (XRD) technique was used for the evolution study of the crystal diameter, stress and volume fraction during the isothermal heat-treatment coupled with spectro-photometric measurement of scattering and interferometric measurement of refractive index change. Based on these results, the effect of NaF crystals on the refractive index change and scattering is assessed.

2. Experimental

2.1. PTR glass preparation

Samples of a photosensitive PTR glass containing $15Na_2O-5ZnO-4Al_2O_3-70SiO_2-5NaF-1KBr-0.01Ag_2O-0.01CeO_2$ (mol.%) and minor amounts of Sn and Sb were used in this work as in previous studies [6,9-10]. The glass was melted in an electric furnace in a 0.5 liter platinum crucible at 1460°C for 5 hours in air and stirred using a Pt blade to homogenize the liquid. After melting, homogenizing and fining, the glass was cooled to the glass transition temperature (T_g ~ 460°C), then annealed at T_g for 2 hours, and cooled to room temperature at a rate of 0.1 K/min. Polished $25 \times 25 \times 2$ mm³ samples were prepared from the batch. The chemical homogeneity of the samples is a critical parameter affecting crystallization properties [11], thus homogeneity was tested by the shadow method in a divergent beam of a He–Ne laser and was quantified by

measurements using an interferometer (GPI Zygo). The samples selected for this study had refractive index fluctuations of less than 40 ppm (peak-to-valley) across the aperture.

2.2. UV-exposure and heat-treatments

UV-exposure of samples was performed by a He-Cd laser (4 mW, 325 nm). Each sample was exposed with maximum dosage of 0.9 J/cm² to a stripe with a single horizontal line scan and to a homogeneous squared area by scanning several overlapped lines on the sample [12]. The samples were first all nucleated for 100 minutes at 485°C and then thermally developed at 515°C for different time length varying from 1 to 72 hours. All heat-treatments had the following sequence: Temperature was elevated from room temperature to 485/515°C at a rate of about 20 K/minutes where they were kept for the designed duration and then cooled down to room temperature in the furnace following the natural decrease of the furnace temperature (about 2.5 K/min). Finally, in order to remove any incipient crystallization on surfaces, each sample was ground and re-polished with flatness better than $\lambda/2$ at 633 nm.

2.3. Refractive index change measurements

Refractive index changes were measured in each sample using a shearing interferometer setup [12]. Its basic principle is to create an interferogram that converts the phase change at propagation through the glass to a fringe shift. A liquid cell with an index matching fluid was used to prevent thickness variations of the sample which would contribute to fringe shift. Therefore the interferometer fringe distortions resulted only from refractive index variations.

2.4. Spectra measurements

Transmission spectra were measured using a Perkin Elmer Lambda 950 spectro-photometer in the range from 200 to 1700 nm. Then, the spectral dependence of the losses coefficient was calculated by subtracting from the transmission spectra, the reflection spectrum of PTR glass that was calculated from the measured refractive index dispersion curve [13]. The absolute precision of such spectro-photometric measurement being limited to about 2.10^{-2} cm⁻¹ i.e. about one order of magnitude larger than its relative precision, each curve was calibrated. To achieve, precise measurement of the transmission and the reflection at 1085 nm was carried out on each sample by photometric measurement using an Yb fiber laser. Then, losses were calculated at this wavelength, with a precision of 10⁻³ cm⁻¹, all spectra were stitched to the measured value of losses at 1085 nm. Using this technique, the absolute precision of each spectrum was improved to 10⁻³ cm⁻¹. Also, as spectro-photometric measurement do not allow separating absorption losses from scattering losses, and the main source of absorption is associated with the presence of the plasmon resonance of Ag containing particles [14], all samples were bleached twice using a focused beam from the second harmonic from a Nd:YAG laser in order to remove the main part of the absorption [15]. That way, it can be shown that more than 90% of the losses measured above 400 nm are only associated with scattering losses. Finally scattering at 633 nm was extracted by fitting each curve with an exponential function as it was shown that this model allows accurate description of the spectral dependence of scattering in PTR glass [14]:

$$S(\lambda) = S_0 \left[\frac{\lambda_0}{\lambda}\right]^4 \text{ with } \lambda_0 = 633 \text{ nm}$$
(1)

2.5.X-ray diffraction measurements

X-ray powder diffraction measurements were performed at room temperature on a Rigaku MiniFlex II using CuK α radiation (λ = 0.15418 nm), with a tube voltage of 30 kV and a tube current of 15 mA. The irradiated and bleached glass samples were pounded to a powder then sieved and the 45 to 75 µm size fraction was packed in a 2 mm deep indented quartz holder. X-ray diffraction patterns were recorded for a 2 Θ scan angle between 20 and 75° in a continuous scan mode with 0.02° sampling width and 0.2 deg/min scan rate. Corrections were made for instrument broadening. Each diffraction pattern showed similar features:

- An amorphous peak 2 Θ from α -quartz at 22.80°
- Three crystalline diffraction peaks 2Θ , identified as sodium fluoride Villiaumite
 - (200) at 38.55°
 - (220) at 55.65°
 - (222) at 69.85°

The (200) peak around 38.55° being the main diffraction peak, a second XRD run was performed at a lower scan rate of 0.02 deg/min from 37.5 to $39.5^{\circ} 2\Theta$ in order to collect more detailed data, all subsequent analysis were carried out on this last measurement.

3. Results

3.1. Evolution of refractive index change and scattering in the process of thermal

treatment

Tab. 1 shows the evolution of the refractive index change (RIC) as a function of the thermal treatment duration. Refractive index change values start reaching saturation at around 1000 ppm for 6 hours thermal treatment time. For thermal treatment durations higher than 6 hours the

saturation is associated with the crystallization of the unexposed part which prevents from carrying out any measurement and makes the glass unusable for any optical application. Tab. 2 shows the temporal evolution of scattering at 633 nm. It can be seen that scattering increases for the first 24 hours close to saturation value, then tends to decrease for the longer thermal treatment time of 36 and 72 hours.

3.2. Evolution and processing of the X-ray diffraction peaks of NaF crystals

Fig. 1 shows the evolution of the main diffraction peak of NaF at ~ 38.5°. One can observe several remarkable features: First each of the diffraction peak exhibits a complex pattern composed by at least two different diffracted bands. Overall the amplitude of each diffracted peak increases when increasing the heat-treatment duration. No significant change in the width can be simply observed while the overall peak tends to shift towards larger angles (faint effect). To refine this analysis, calculations were performed on each diffraction pattern. The observed peak shapes are best described by peak shape functions, the most commonly used peak shape functions are as follow: Gaussian functions [16], Lorentzian functions [16], or Pseudo-Voigt, i.e. a combination of both [16]. In our case the best and most convenient model is the simple Gaussian distribution:

$$I^{G}_{i,k} = G_0 exp\left(-\frac{(2\theta_i - 2\theta_i)^2}{2\sigma_{\theta}^2}\right)$$
(2)

Where σ_{θ} is the FWHM, $2\theta_i$, the Bragg angle of #i point and $2\theta_k$, calculated Bragg angle. To fit each diffraction peak, the background was first subtracted. Since the CuK α radiation is not strictly monochromatic, the Bragg peak is a convolution of the individual K $_{\alpha 1}$ and K $_{\alpha 2}$ peaks with the respective wavelength λ_1 =1.54406 Å and λ_2 = 1.5444 Å, and therefore it was necessary to

perform a $K_{\alpha 2}$ stripping. Since every $K_{\alpha 1}/K_{\alpha 2}$ double peak is caused by scattering from a single lattice point, the *d*-spacing remains the same constant and the scattered intensity is proportional to the intensities of the two components. Using Bragg's law, the relationship between the positions of the diffracted peaks in the doublet is defined by: $\sin\Theta_1/\lambda_{K\alpha 1} = \sin\Theta_2/\lambda_{K\alpha 2}$. In addition, their integrated intensities are related as: $I^{G}(K\alpha_{1}) = 2 I^{G}(K\alpha_{2})$. Finally, common assumption that both peaks have identical shapes at lower diffraction angles was made [16]. Using the parameters of the Gaussian function used to fit the $K_{\alpha 1}$ peak, the peak position, 2 Θ , the peak position intensity, I, the crystallite diameter, D and the crystallite fraction volume fraction, $V_{\rm f}$ were estimated. Typical decomposition of the (200) diffraction peak of NaF powder is shown in Fig. 2-a and Fig. 2-b and 2-c show similar fit performed on (200) peak measured after respectively 2 and 6 hours at 515°C. While this model could not take into account some of the fine features of the diffraction pattern, the overall shape could be well represented with such a simple model. From the fitted parameters for $K\alpha_1$ the evolution of the peak intensity, its position and the full width at half maximum during the crystallization process were respectively plotted in Figs. 3-a, 3-b and 3-c. Such an evolution is the signature of a change of the volume fraction, the crystal size and the stress surrounding each crystal during the thermal treatment process. The area under the diffraction peak was also calculated for all heat-treatment durations in both unexposed and UV-exposed glass. It is well known that this area is proportional to the volume fraction of crystals generated in the glass ceramics [16]. In order to extract the later parameter, a calibration curve was created by mixing virgin PTR glass powder with different known volume fractions of NaF crystals (Fig. 4). It is worth noting that due to similar densities of NaF and PTR glass, volume fractions of NaF in vol.% are only 10% higher than the fraction of NaF in wt.%. The evolution of the area under the curve as a function of the volume fraction of NaF crystals in

wt.% can be accurately fitted using a linear function with a slope equal to 35.6 area-unit/wt.%. Using this calibration curve, the dependence of NaF crystals volume fraction on thermal treatment duration was calculated and plotted in Fig. 5 for both unexposed and UV-exposed glass. The volume fraction evolution of UV-exposed PTR glass is similar to that of the peak intensity. Moreover, crystallization of unexposed PTR glass occurs after some longer induction time corresponding to the refractive index change saturation.

4. Discussion

The evolution of the optical and structural properties of PTR glass was presented. This section presents some further analysis of these data and a correlation between these optical and structural properties. First of all, from the position of the diffraction peak as shown in Fig. 3-b, the stress surrounding the NaF crystals could be extracted. It is known that stress surrounding crystals produces a shift of the diffraction peak [17]. A shift towards lower angle corresponds to stretched crystals. Stress calculation can be performed using the following formulae:

$$\sigma = \frac{E_p}{(1-2\nu_p)} \frac{\Delta d}{d} \tag{3}$$

Bragg law:

$$n\lambda = 2dsin(\theta) \tag{4}$$

Where E_p is the Young modulus, v_p , the Poisson ratio, $\Delta d/d$, the relative change of the NaF lattice parameter, λ the X-ray radiation wavelength and θ the Bragg angle. Calculation show that after one hour of thermal treatment at 515°C, stress is equal to ~1.3 GPa while after 72 hours, stress is decreased to ~900 MPa. In other words, relaxation of the NaF crystals happens during the thermal treatment. It is important to note that the measured stresses are similar to the one

measured by NMR [18] or by synchrotron [17]. Moreover, this stress is a key parameter in the photo-thermo-refractivity of PTR glass as it was shown to play a major role in the appearance of refractive index change through the glass photo-elasticity [19].

Combining the data of the Figs 3-b and 3-c allowed extracting one more parameter: the evolution of the mean crystal diameter using the Scherrer formula [20]:

$$D = K\lambda / (\sigma_1 \cos \theta)$$
⁽⁵⁾

$$\sigma_1{}^2 = \sigma_{\theta,1,\exp}{}^2 - \sigma_{\theta,1,inst}{}^2 \tag{6}$$

where K is the Scherrer constant with a value of 1 for spherical particles, $\sigma_{\theta,1,exp}$ is the FWHM measured on the sample, $\sigma_{\theta,1,inst}$ is the instrument peak broadening that can be easily determined using crystalline NaF standard as shown in Fig. 2-a, θ is the Bragg angle and λ the wavelength. Fig. 6 shows the evolution of the average crystal diameter as a function of thermal treatment duration. The average NaF crystal diameter increases until reaching saturation. However, one can see that the apparent diameter reaches 16 nm within the first hour then saturates to ~ 20 nm, showing that, either most of the growth occurs very fast or is a complex mechanism. The evolution of the volume fraction of crystals as a function of the thermal treatment duration was showed in Fig. 5. The volume fraction increases by 4 times when the heat treatment duration is increased from 1 to 72 hours; this represents the saturation in crystal volume fraction that can be formed in this glass at this temperature [21], while the average crystal diameter only increases by 20% during the same thermal treatment period. Therefore, the increase of the crystals volume fraction can only be explained by an increase in the crystal number density. Using basic chemistry equations, the evolution of the crystal number density, the evolution of the average distance separating the NaF crystals and the average diameter of the Na⁺F⁻depleted glass zone, due to the creation and growth of NaF nano-crystals could be calculated (Tab. 3). At saturation,

the crystals have an average diameter of 20 nm and a density of 5×10^{21} m⁻³. Saturation corresponds to a crystal-to-crystal distance comparable to the diameter of the NaF depleted zone of ~ 60 nm which corresponds to three times the crystal diameter. This average distance between crystals decreases during the thermal treatment and can very easily explain the data of the Fig. 3b and calculated stresses surrounding NaF crystals. While this distance decreases, the interaction between the depleted zones increases, this results in stress compensation of the glass and therefore affects the NaF crystals. It is also worth noting that the crystal number density reaches almost 50% of its value at saturation within the first hour of thermal treatment and that the average crystal diameter undergoes only a small change during the thermal treatment duration. This result shows that crystallization is a fast process at a 515°C temperature. Glasses were nucleated for 100 minutes at 485°C which allowed abundant nucleation of the glass and in turn triggered fast growth of 50% of the crystals within the first hour of the thermal treatment. But, due to the limited amount of fluorine in the glass, the mentioned crystals cannot grow at 515°C to diameters much larger than 20 nm and the increase of the volume fraction of NaF crystals is therefore explained by further nucleation and growth of NaF nano-crystals on these new sites.

Using the data of Figs. 5 and 6 some additional calculations were performed. Tab. 2 presents the evolution of scattering as a function of thermal treatment duration. Scattering in PTR glass appears only after the glass has been exposed and developed at high temperature and NaF nanocrystals, which have a refractive index (1.32) lower than the one of the glass matrix (1.5), have been created. It was shown in Ref. [14] that scattering is a spectral dependence following a λ^{-4} law typical of classical Rayleigh scattering [22]. Rayleigh scattering regime is defined by scattering from objects with a size which is much smaller than the wavelength of the light. In this case scattering has a linear dependence on volume fraction of crystals and fourth power dependence on the crystal radius as follow:

$$S \propto V_f r^4$$
 (7)

where V_f is the volume fraction of crystals and r the average NaF radius. In order to confirm that scattering is produced by individual NaF crystals and not by clusters of crystals or any other sites with a refractive index different from that of the glass matrix (such as droplets produced by liquid-liquid phase separation [23]), the dependence of scattering on $V_f r^4$ was plotted in Fig. 7. Except for the last two experimental points, the scattering losses have a linear dependence on $V_f r^4$, confirming that scattering is produced by individual NaF crystals. Further analysis have also shown that based on the volume fraction of crystals, their size and the refractive index contrast between NaF crystals and glass matrix, it is possible to fully model (using the radiation transfer theory) and predict scattering losses for any thermal treatment with duration less than 24 hours. The loss of linear dependence of scattering on $V_f r^4$ for thermal treatment with duration more than 24 hours can then be attributed to two effects: first, liquid-liquid phase separation is very likely to occur and to contribute to a different type of scattering that cannot be predicted by Rayleigh scattering [23]; moreover, when the glass is close to be depleted in Na⁺F⁻, the growth rate decreases resulting in a shift to a coarsening (or Ostwald ripening) regime [24]. This new regime results in the creation of dendrites which cannot be easily characterized by X-ray diffraction and cannot be modeled using Rayleigh scattering model. The relation between the refractive index change and the volume fraction of crystals and size was also investigated. It was shown in Ref [6] that refractive index linearly dependents on volume fraction of NaF crystals. To confirm this data, the dependence of refractive index change von NaF crystals volume fraction was plotted in Fig. 8. In a first approximation, the refractive index change is in part linearly

dependent on NaF crystals volume fraction. However, there are some deviations from linearity that can be related to the mechanisms of refractive index change in PTR glass. Actually, as already mentioned above, refractive index changes in homogeneously exposed glasses are mostly due to stresses surrounding NaF nano-crystals [19]. In addition, from Fig. 3-b, it was shown that stress is not constant during the thermal treatment duration. Therefore, refractive index change can only partially be a function of the crystal volume fraction.

The cause of the NaF crystals size saturation at ~20 nm was finally investigated. PTR glass samples were exposed at 325 nm with a dosage of 0.9 J/cm², then iso-thermally heat-treated in a Differential Scanning Calorimeter (DSC) at different temperatures ranging from 515 to 600°C and stopping the heat-treatment after overall crystallization occurred, i.e. a temperature distinctly above that of the end of the crystallization peak. Observation of these DSC treated samples (Fig. 9) shows that depending on the thermal treatment temperature, UV-exposed samples have dramatically different appearance; the samples heat-treated at temperatures of 570°C or below are translucent, while the samples heat-treated at temperature of 590°C and above are opaque and whitish. This difference of appearance is associated with significantly different levels of scattering, showing that the size of the created crystals is most probably different. To confirm this hypothesis, the X-ray diffraction patterns of samples heat-treated at 550 and 600°C were measured and all the basic crystals parameters were extracted from these measurements (Tab. 4). First of all, the parameters measured in the sample heat-treated at 550°C are very similar to the one measured in the sample heat-treated for 72 hours at 515°C that was studied previously, confirming that overall crystallization was achieved. However, the sample heat-treated at 600°C shows different features; the volume fraction of crystals measured is comparable to that of the

 550° C heat-treated sample. The NaF solubility being comparable at 550 and 600°C, this result confirms that in both cases, overall crystallization was reached. However, after heat-treatment at 600°C, the average crystal diameter is 30 nm, i.e. 50% larger than after 550° C-heat-treatment (this size is probably limited by the peak broadening due to the apparatus function) and peak position is at larger angle, which corresponds to a decrease of the stress surrounding these crystals (and this results correlates the results of Fig. 3-b and 6, i.e. the stress decreases while the average crystal diameter increases). Similar effect of limited growth was already observed in glasses with similar composition as PTR but with CaF² or BaF² nano-sized crystals and was explained by the presence of F-depleted diffusion-barriers zones surrounding each crystals. To analyze the results in PTR glass [25-26], one must take into account the structure presented in Ref [19]. After thermal development, the glass has three different regions:

- The first area is a cubic sodium fluoride
- As sodium and fluorine ions are consumed by the growing crystals, halos with the same components as virgin PTR glass, but are depleted in sodium and almost exhausted in fluorine are formed.
- The third area, far away from the crystals, is an unperturbed glass region having identical composition as virgin PTR glass.

The region of interest is the intermediate region which has the composition of PTR glasses but is depleted in fluorine. Due to this depletion, the glass has an increased glass transition temperature with a value expected to be similar to the one of soda-lime silicate glasses, i.e. around 580°C. This result could not be experimentally confirmed as decreasing the NaF content of PTR glass results in a fast increase of the melting temperature which makes it hardly possible to melt with our technological capabilities. When glasses are developed below the glass transition

temperature of this intermediate glass, it acts as a barrier for the growth of large NaF crystals, which explains the fast saturation of crystal diameter to a value of ~20 nm. When this glass transition temperature is overcome, further NaF crystal growth and coarsening can occur resulting in larger crystals and bulk scattering.

5. Conclusion

The NaF growth in PTR glass was studied by combining optical spectroscopy, interferometry, DSC and XRD. The size of NaF crystals in UV-exposed PTR glass as determined by the broadening of diffraction lines was shown not to exceed ~20 nm. The NaF crystals growth limiting parameter is the exhaustion of Na⁺F⁻ within the glass matrix as well as the increase of the glass transition temperature of the glass surrounding the NaF crystals, it acts as a barrier for further NaF crystal growth. Combining size and volume fraction of NaF crystals in PTR glass with Rayleigh scattering model allowed predicting scattering at any wavelength and thermal treatment schedule, proving that overall scattering is determined by the sum of the scattering of each individual crystals. Finally, due to the mechanisms at the origin of these changes, the dependence of the refractive index change on crystal volume fraction is only partially linear.

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8. Tables and Figures

Thermal treatment duration, hours	RIC, ppm		
1	329		
1.5	546		
2	649		
3	809		
4	873		
5	905		
6	957		

Tab. 1. Evolution of the refractive index change versus thermal treatment duration at 515°C in

PTR glass exposed to 0.9 J/cm^2 at 325 nm and pre-nucleated for 100 minutes at 485° C.

Thermal treatment duration, hours	Scattering @ 633 nm, cm ⁻¹			
1	0.079			
1.5	0.115			
2	0.154			
3	0.211			
4	0.248			
5	0.319			
6	0.331			
12	0.411			
24	0.513			
32	0.467			
72	0.412			

Tab. 2. Evolution of the scattering losses at 663 nm versus thermal treatment duration at 515°C

in PTR glass exposed to 0.9 J/cm² at 325 nm and pre-nucleated for 100 minutes at 485°C.

		D-NaFatoms	0.95	nm	
		a-NaF	0.33	nm	
Thermal treatment duration, hours	Volume fraction, vol.%	Crystal diameter, nm	Number of crystals per m3	Distance between NaF crystals, nm	Diameter depleted zones, nm
1	0.47	15.77	2.27×10^{21}	76.05	45.60
1.5	0.54	16.98	2.10×10^{21}	78.14	49.10
2	0.82	16.98	3.19×10 ²¹	67.95	49.10
3	1.12	17.31	4.12×10^{21}	62.36	50.05
4	1.27	17.64	4.43×10^{21}	60.91	51.01
5	1.33	17.99	4.35×10^{21}	61.27	52.02
6	1.45	18.34	4.50×10^{21}	60.55	53.03
12	1.61	18.72	4.69×10^{21}	59.74	54.13
24	1.83	19.1	5.02×10^{21}	58.40	55.23
32	1.91	19.56	4.87×10^{21}	58.98	56.56
72	2.06	19.88	5.00×10 ²¹	58.47	57.48

Tab. 3. Evolution of the volume fraction, crystal diameter, crystal number density, average

distance between crystals and the diameter of the depleted zones as a function of thermal

treatment duration at 515° C in PTR glass UV-exposed with 0.9 J/cm².

Temperature, °C	2 theta, degree	FWHM, degree	Intensity, counts	Diameter, nm	Vf, wt.%
550	38.57	0.53	127	21	2
600	38.62	0.37	200	31	2.25

Tab. 4. Parameters measured by X-ray diffractometer in UV-exposed PTR glass developed at

550°C and 600°C after completing overall crystallization as measured by isothermal DSC.

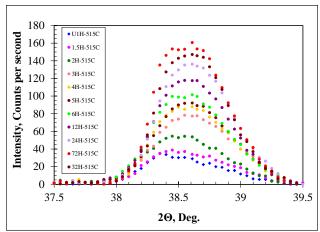


Fig. 1. Evolution of the X-ray diffraction peak of NaF crystals measured in PTR glass exposed to 0.9 J/cm^2 at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C

for different durations.

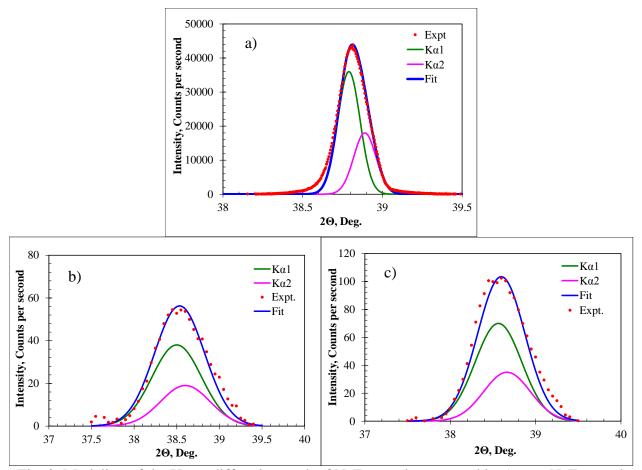


Fig. 2. Modeling of the X-ray diffraction peak of NaF crystals measured in a) pure NaF crystal powder b) PTR glass exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed for 2 hours at 515°C c) similar PTR glass as b) but thermally developed for 6 hours at 515°C.

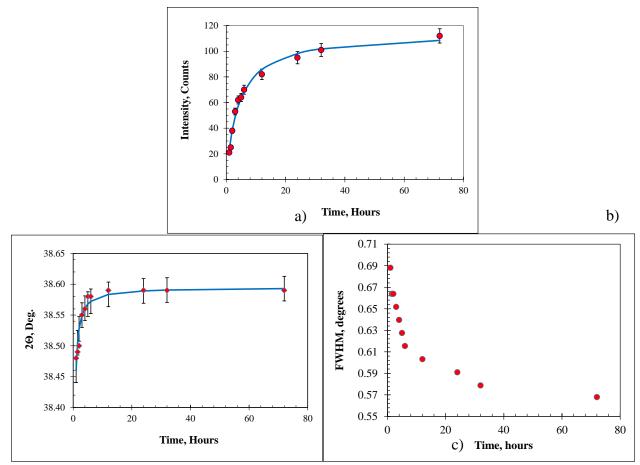


Fig. 3. Evolution of the parameters (peak intensity (a), position (b) and FWHM (c)) extracted from the X-ray diffraction peak of NaF crystals measured in PTR glass exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C for different durations.

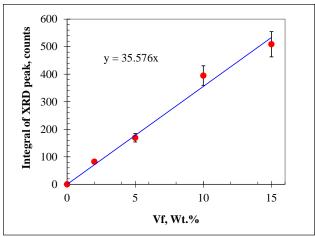


Fig. 4. Calibration curve for the volume fraction of NaF crystals measured by mixing virgin PTR glass powder with known volume fraction of pure NaF crystals powder and measuring the X-ray diffraction pattern.

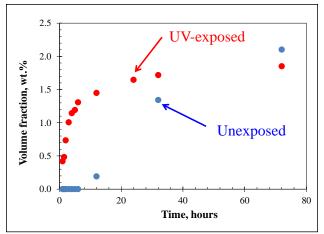


Fig. 5. Evolution of the volume fraction of NaF crystals measured in PTR glass exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C for different durations (Red curve). For reference the evolution of the volume fraction of NaF crystals measured in unexposed PTR glass thermally treated in the same condition is shown

(Blue curve).

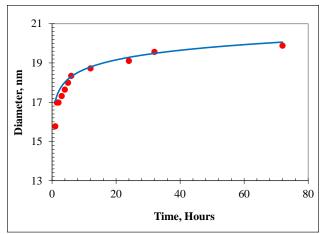


Fig. 6. Evolution of the average NaF crystal diameter extracted from the NaF X-ray diffraction peak measured in PTR glass exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C for different durations.

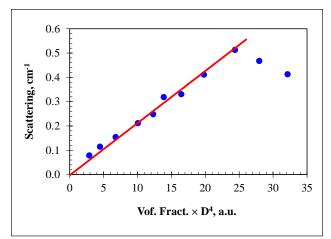


Fig. 7. Evolution of the scattering at 633 nm measured in PTR glass exposed to 0.9 J/cm^2 at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C for different durations (Blue dots) as a function of the product between the NaF crystals volume fraction and

the fourth power of the crystal radius, and its fit using a linear function (red line).

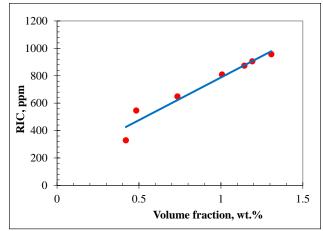


Fig. 8. Evolution of the refractive index change measured in PTR glass exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and thermally developed at 515°C for different durations as a function of the NaF crystals volume fraction.

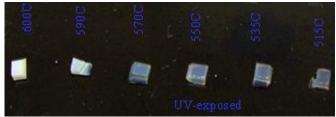


Fig. 9. Pictures of PTR glass samples exposed to 0.9 J/cm² at 325 nm, pre-nucleated for 100 minutes at 485°C and isothermally treated in DSC at different temperature until reaching

overall crystallization.